

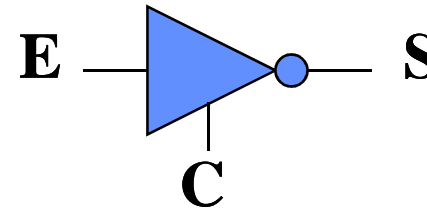
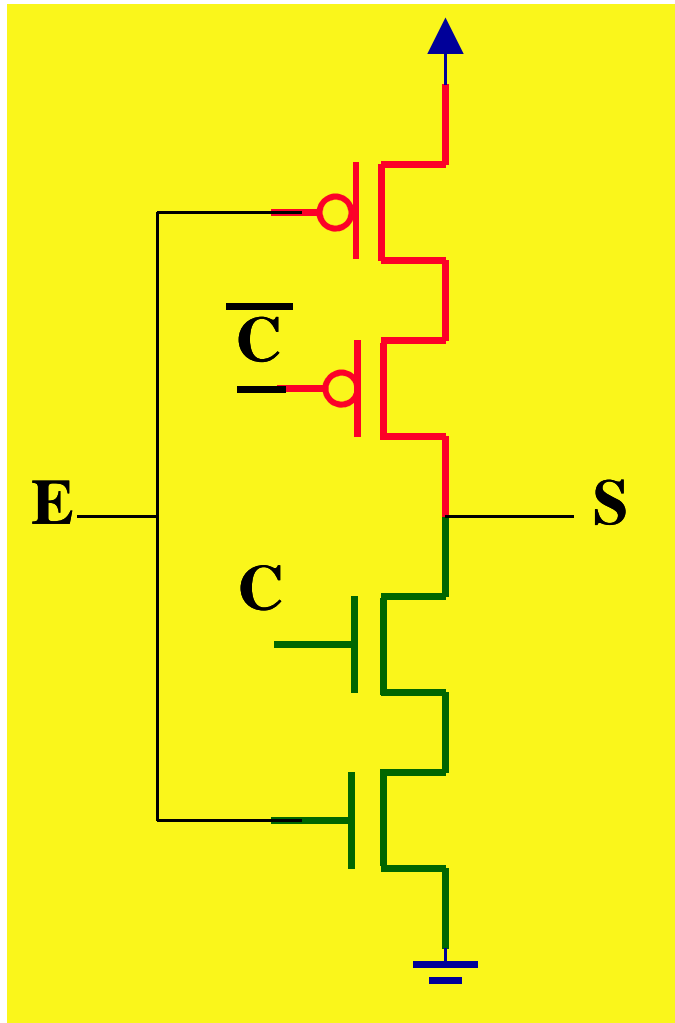
INF01 118

Técnicas Digitais para Computação

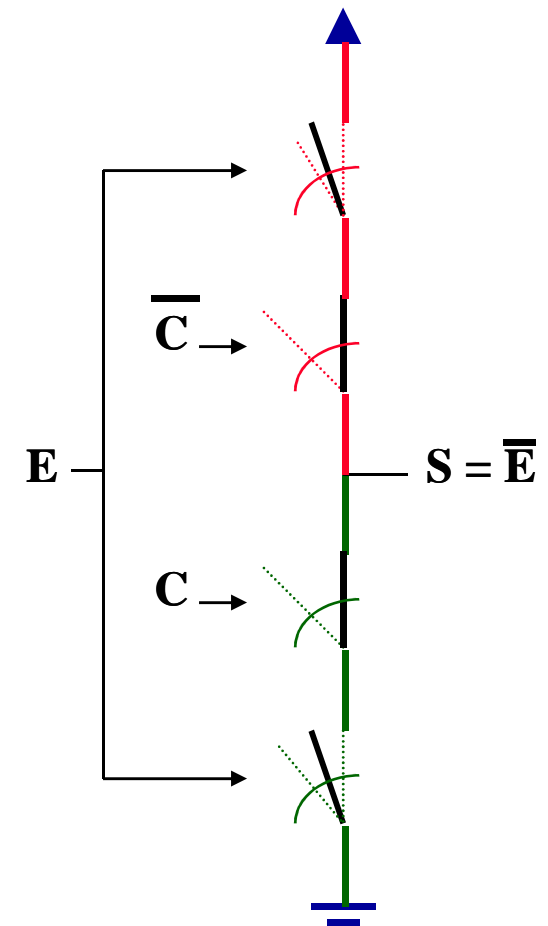
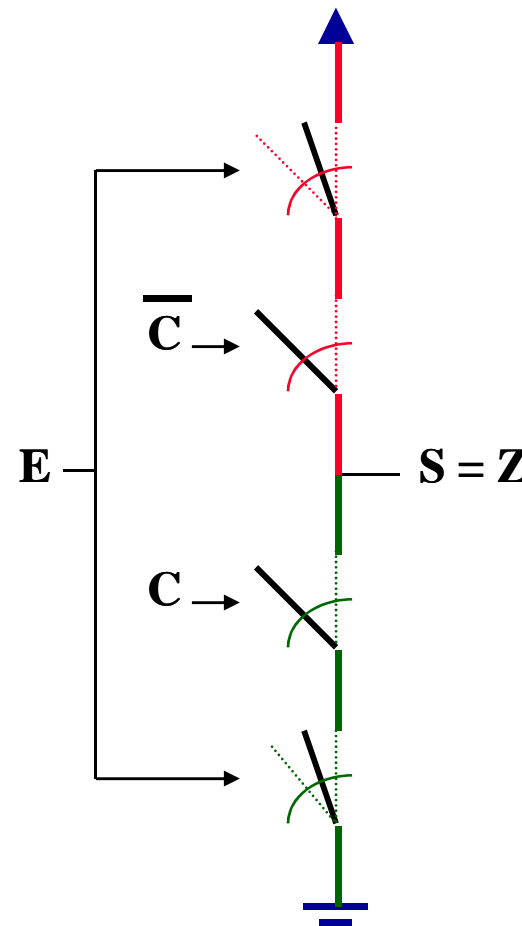
Alta Impedância
Parasitas RC em Portas CMOS
Célula RAM

Alta Impedância (Z)

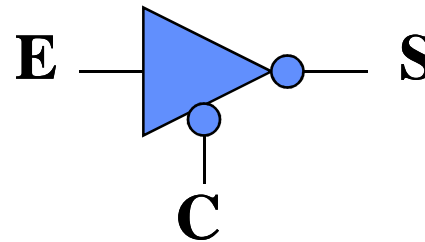
Inversor Tri-State (INVTR)



E	C	\overline{C}	S
0	0	1	Z
1	0	1	Z
0	1	0	1
1	1	0	0



Outra opção...
(controle negado)

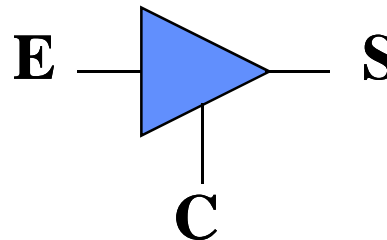


E	C	S
0	0	1
1	0	0
0	1	Z
1	1	Z

OU

C	S
0	\overline{E}
1	Z

Buffer Tri-State
(BUFTR)

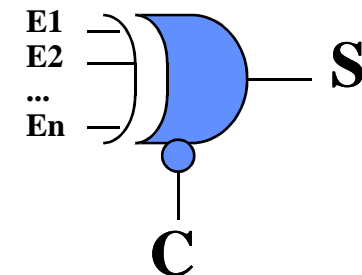
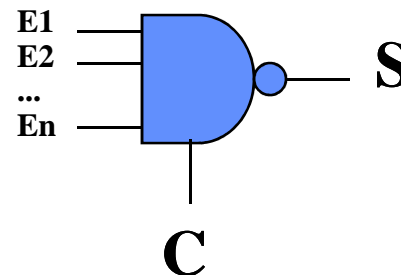
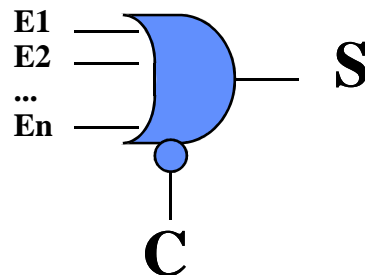


E	C	S
0	0	0
1	0	1
0	1	Z
1	1	Z

OU

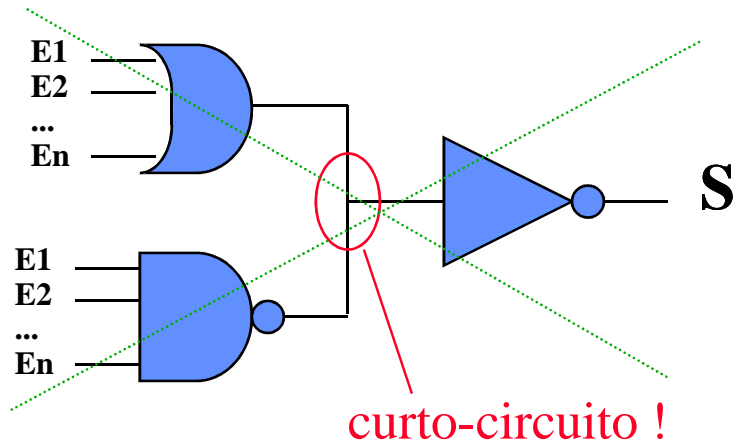
C	S
0	Z
1	E

*** PODE-SE PENSAR EM QUALQUER PORTA LÓGICA
COM SAÍDA TRI-STATE OU ALTA-IMPEDÂNCIA (Z) !!!**

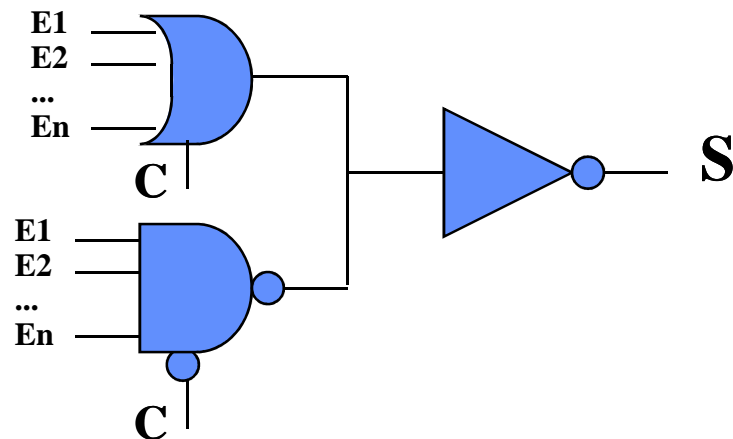


Uso de Porta Tri-State ...

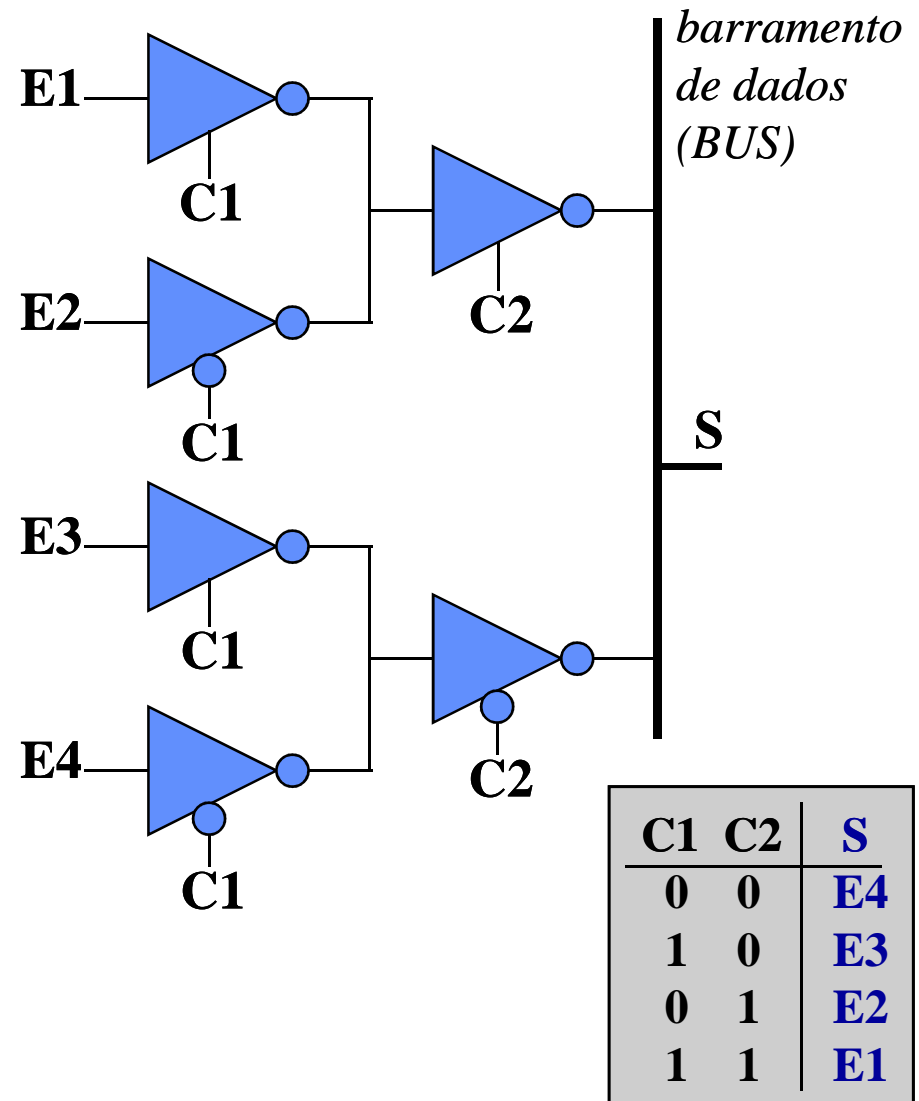
*** NÃO É PERMITIDO EM CMOS :**



*** CORRETO :**

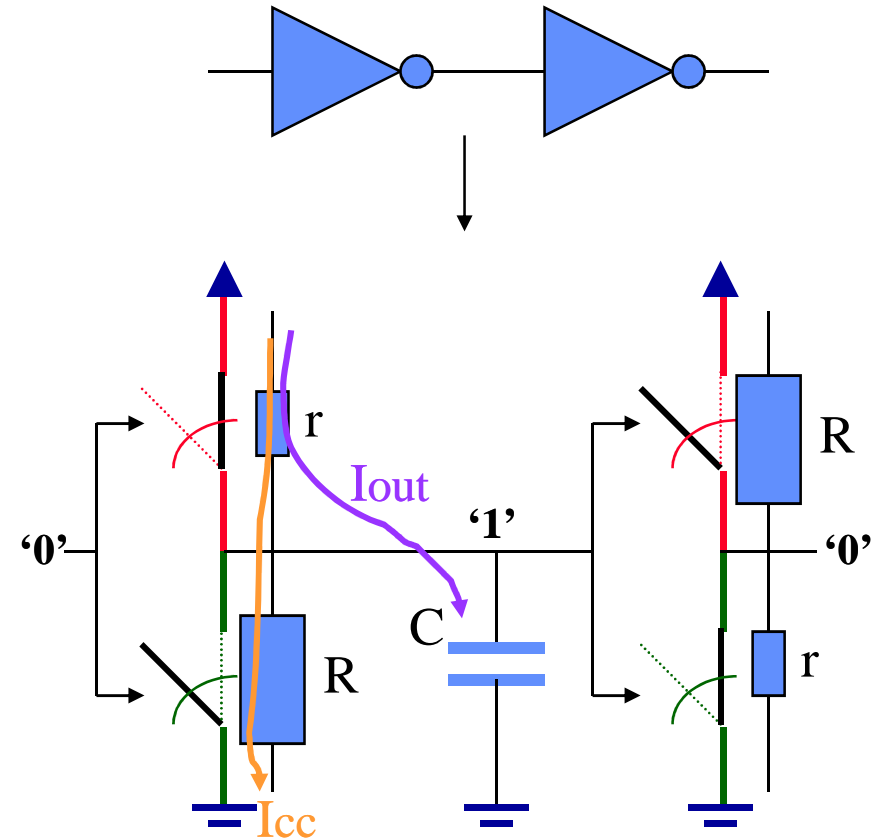
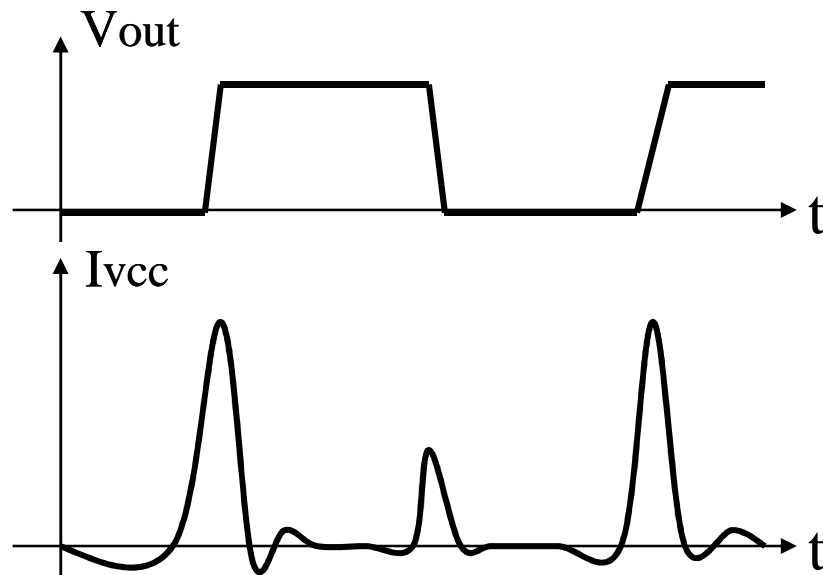


*** BARRAMENTO DE SINAIS :**



Consumo (Dissipação de Potência)

- Corrente de Carga: I_{out}
- Corrente de Curto-Circuito: I_{cc}
- consumo estático ≈ 0
- consumo dinâmico (transição) = $I_{out} + I_{cc}$
- consumo total = estático + dinâmico

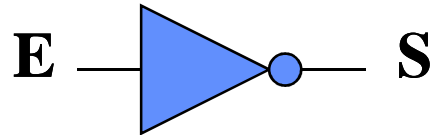


* A variação de W e L afeta o tempo de transição dos sinais e o consumo da porta lógica.

Portas Lógicas (revisão ...)

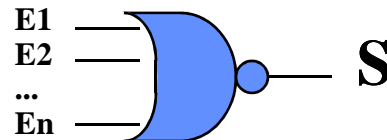
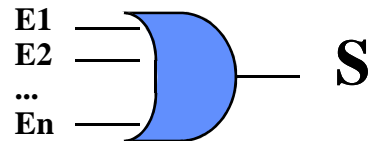
INV

$$E = \bar{S}$$



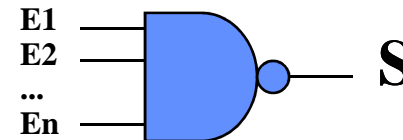
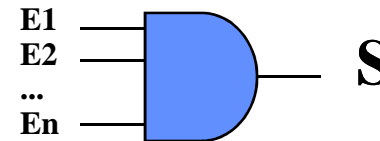
**OR
(NOR)**

$$S = E1 + E2$$



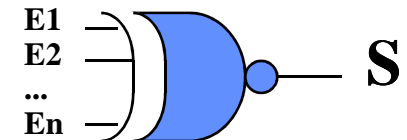
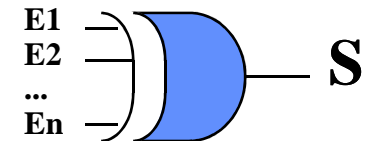
**AND
(NAND)**

$$S = E1 \cdot E2$$



**XOR
(XNOR)**

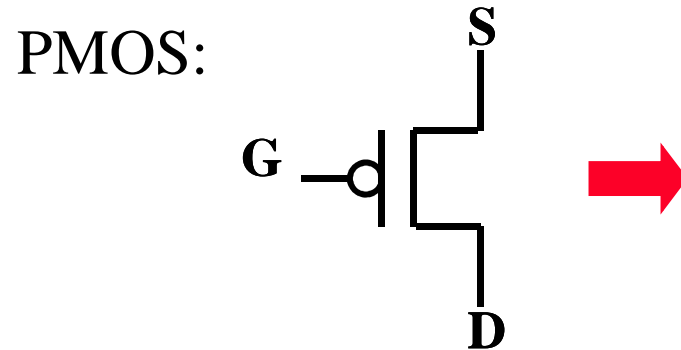
$$S = E1 \oplus E2$$



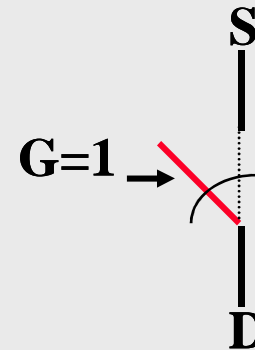
E	INV
0	1
1	0

E1	E2	AND	NAND	OR	NOR	XOR	XNOR
0	0	0	1	0	1	0	1
0	1	0	1	1	0	1	0
1	0	0	1	1	0	1	0
1	1	1	0	1	0	0	1

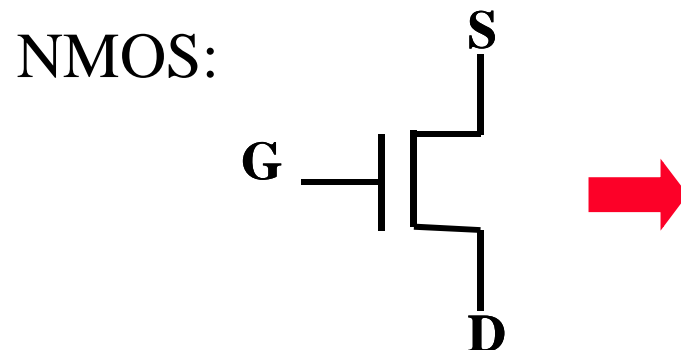
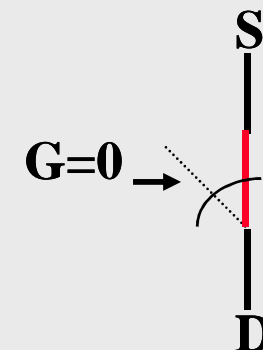
Transistores PMOS e NMOS (revisão ...)



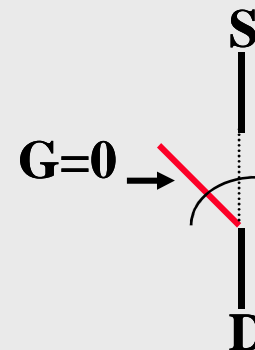
Se $G = 5V$ ('1')
Chave aberta (off)



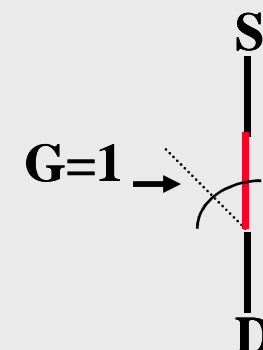
Se $G = 0V$ ('0')
Chave fechada (on)



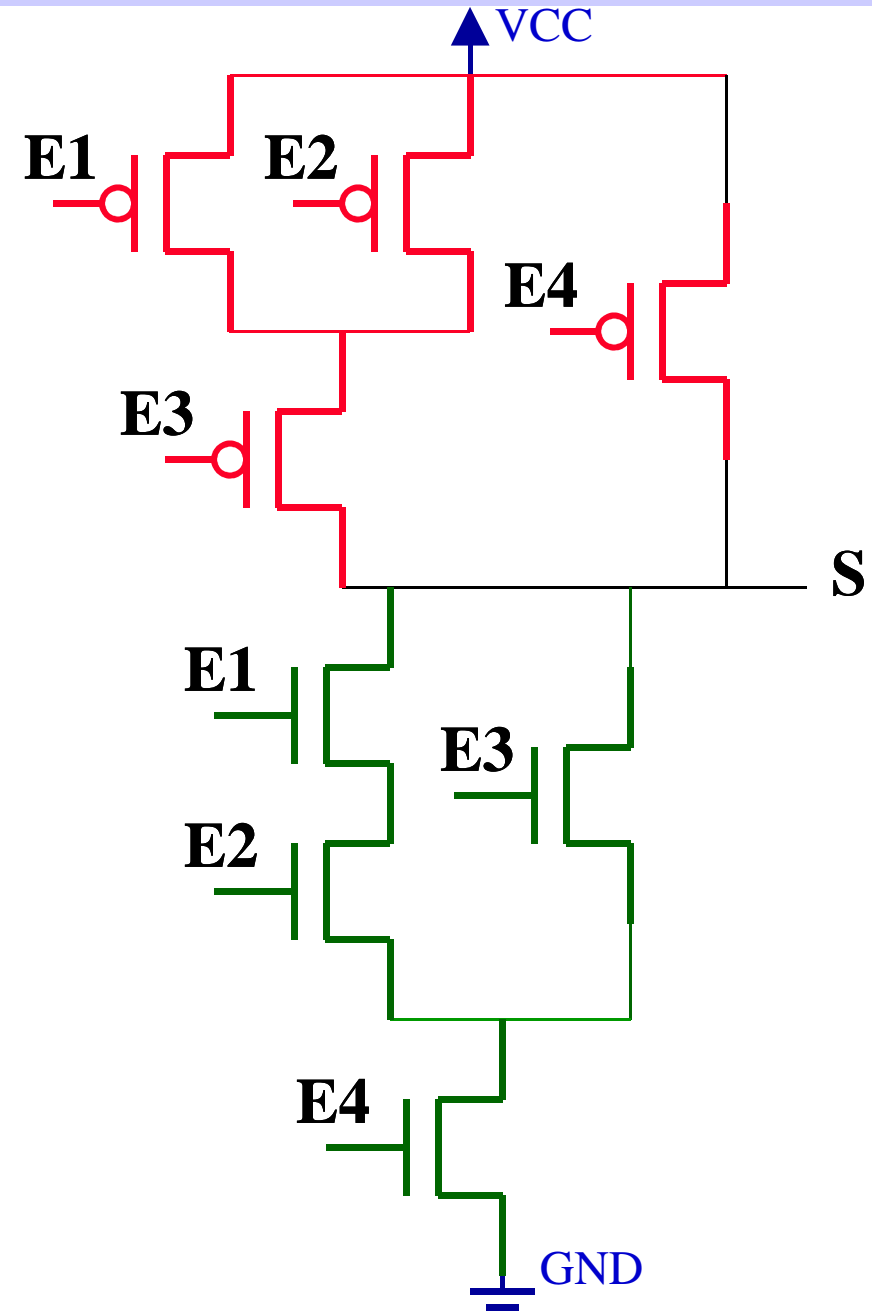
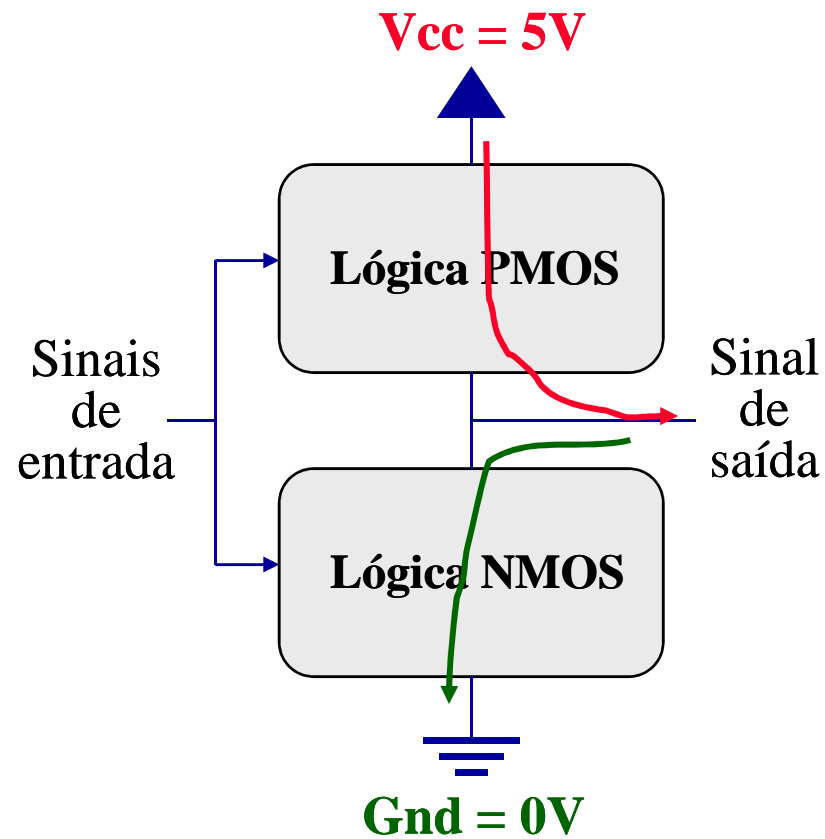
Se $G = 0V$ ('0')
Chave aberta (off)



Se $G = 5V$ ('1')
Chave fechada (on)



Porta Lógica CMOS (revisão)

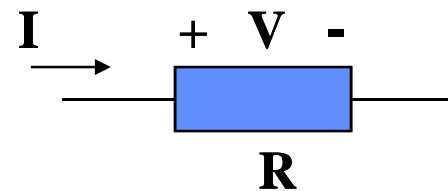
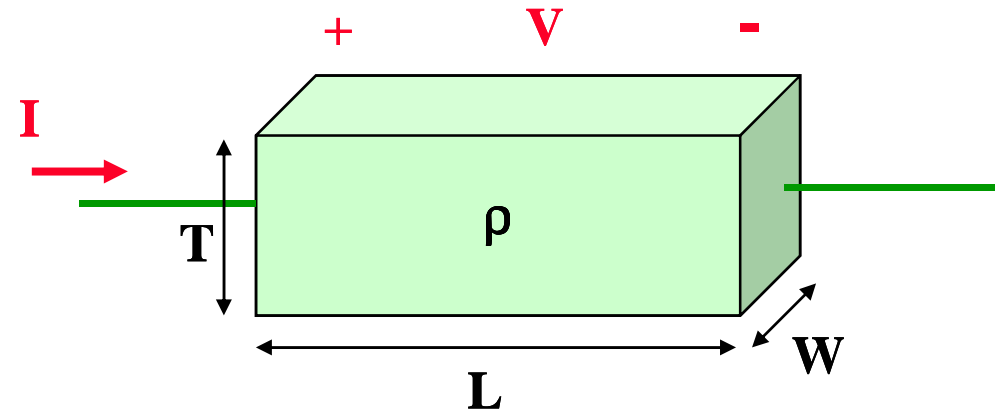


Resistência (R)

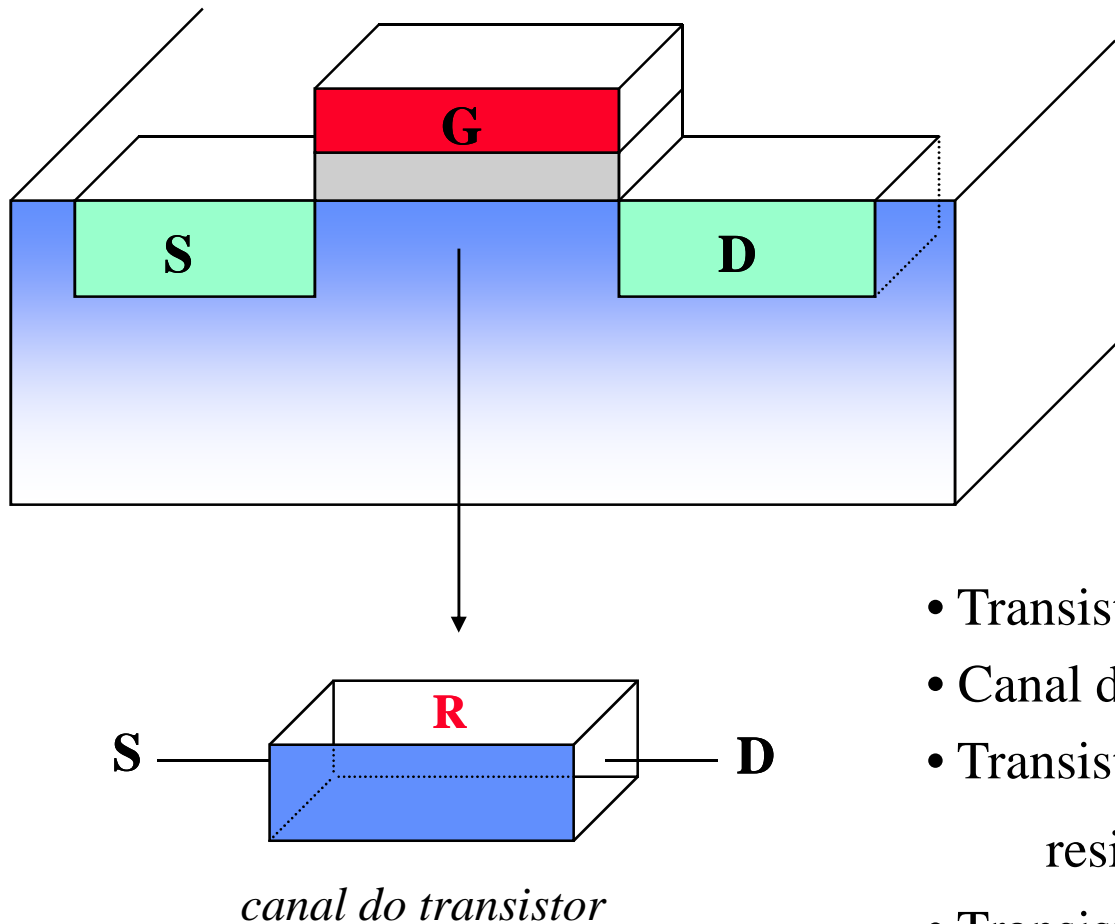
$$R = \rho \cdot \frac{L}{W \cdot T}$$

Lei de Ohm:

$$R = V / I$$

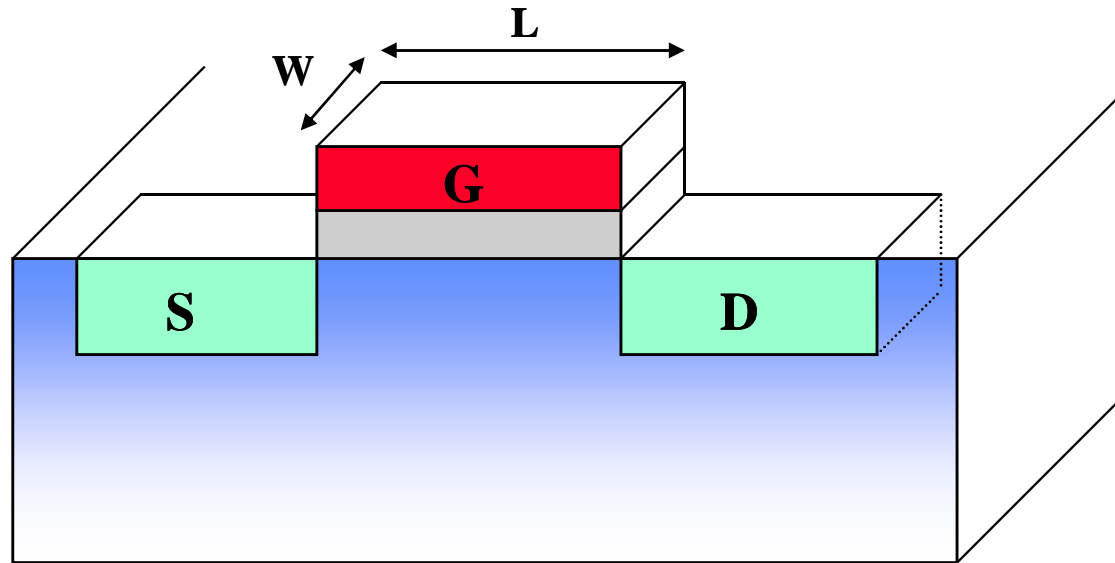


Resistência de Canal do Transistor



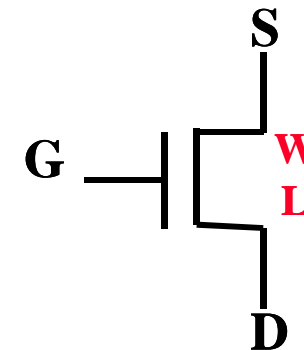
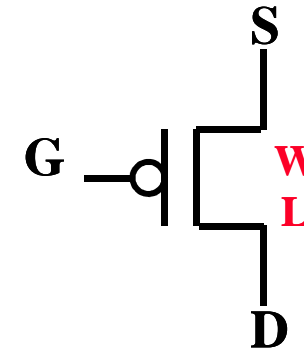
- Transistor não é 'chave ideal'.
- Canal do transistor \Rightarrow resistência
- Transistor conduzindo:
resistência pequena ($R \Rightarrow 0$)
- Transistor 'cortado':
resistência muito alta ($R \Rightarrow \infty$)

Dimensionamento do Transistor MOS

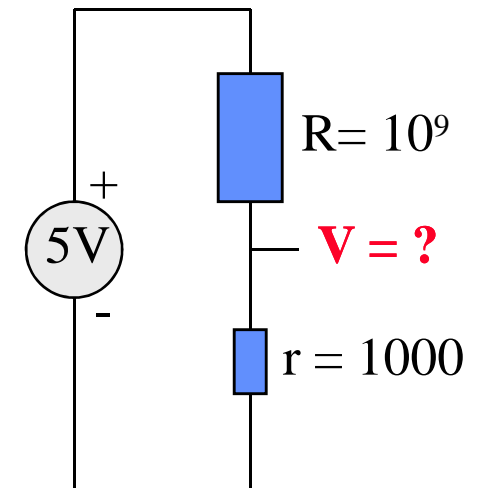
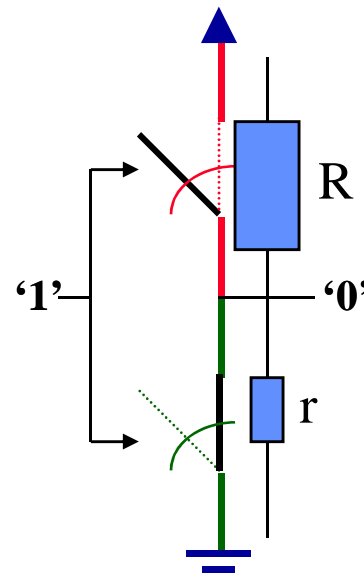
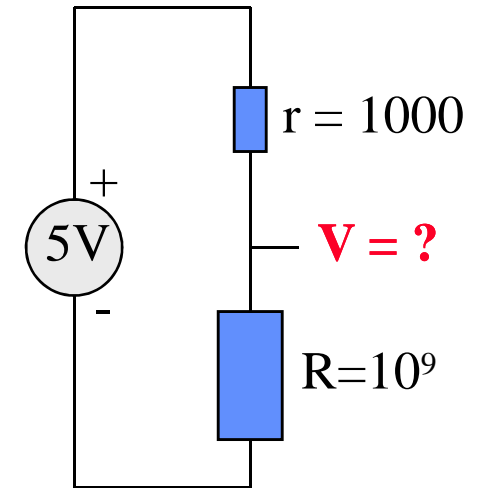
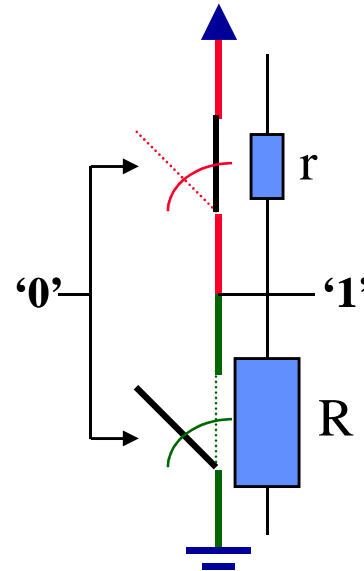
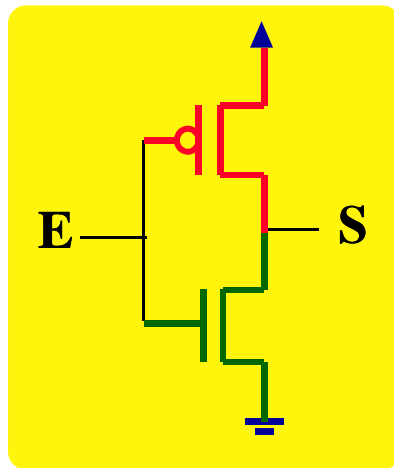


Análise de 'r' ('on') e C:

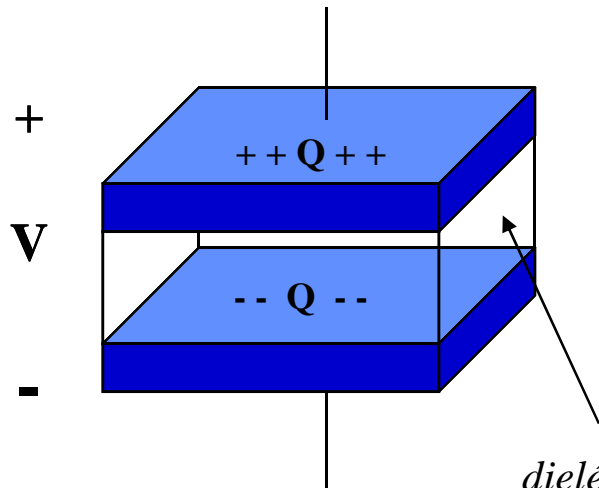
- $W \uparrow : r \downarrow \text{ e } C \uparrow$
- $L \uparrow : r \uparrow \text{ e } C \uparrow$



Inversor CMOS : (resistência parasita)

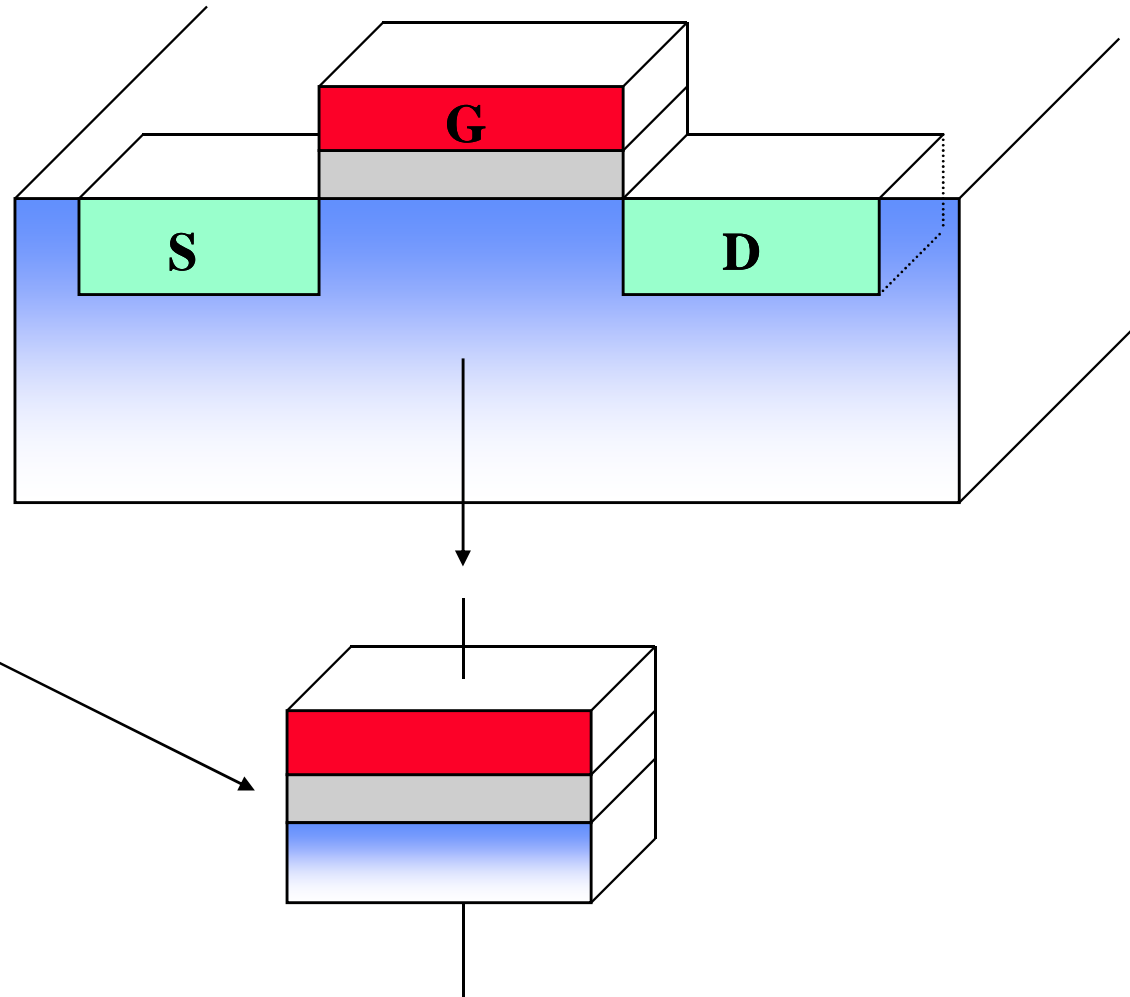


Capacitância (C)

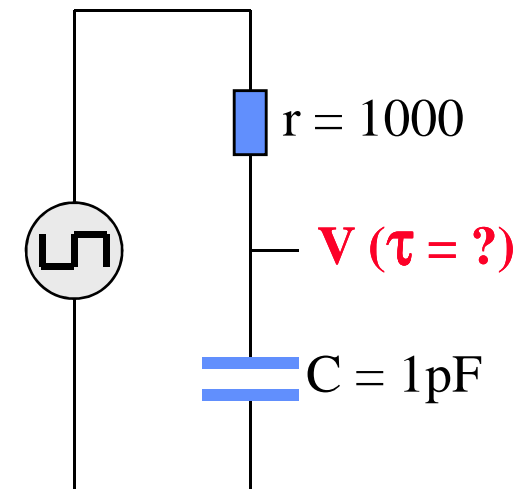
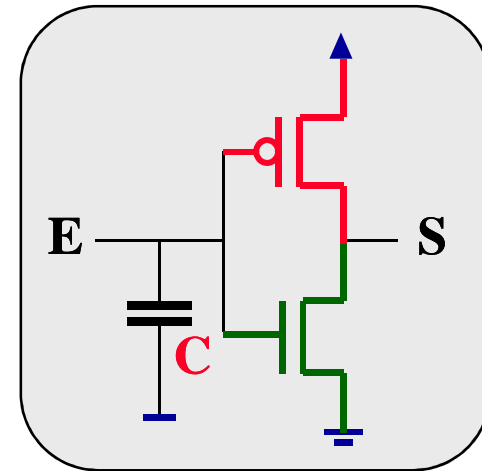
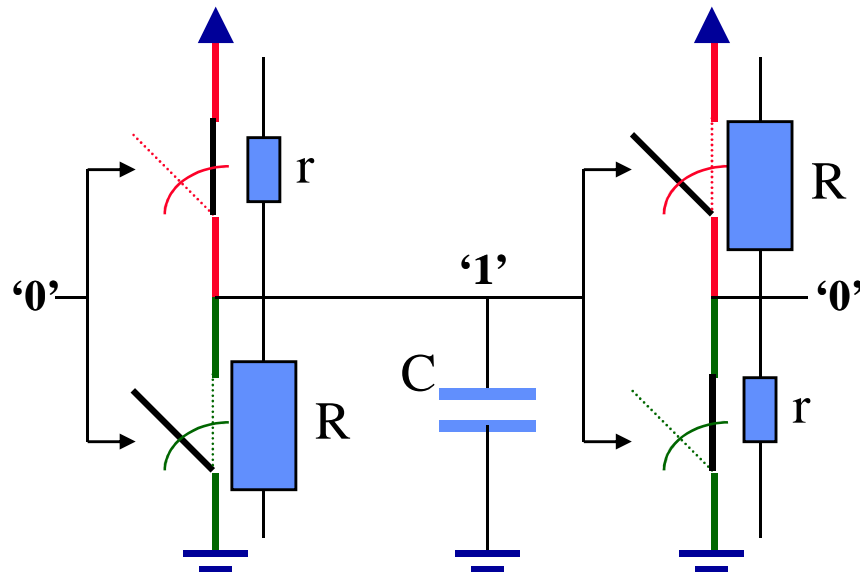
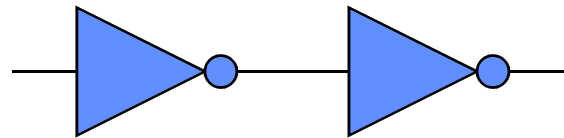


*dielétrico
(isolante)*

$$C = dQ / dV$$

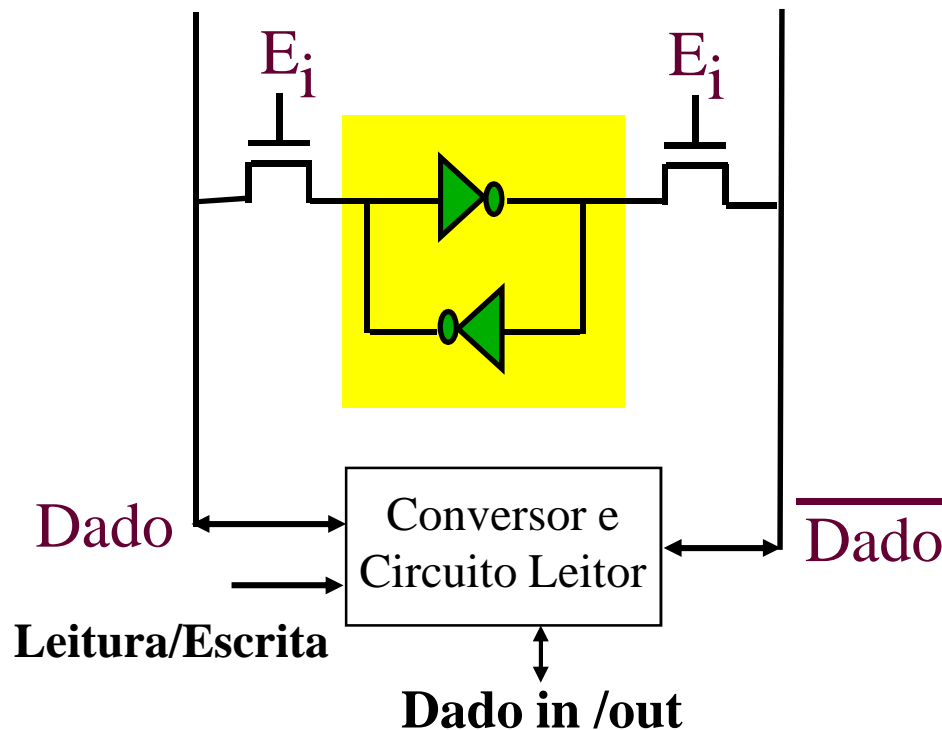


Inversor CMOS : (capacitância parasita)

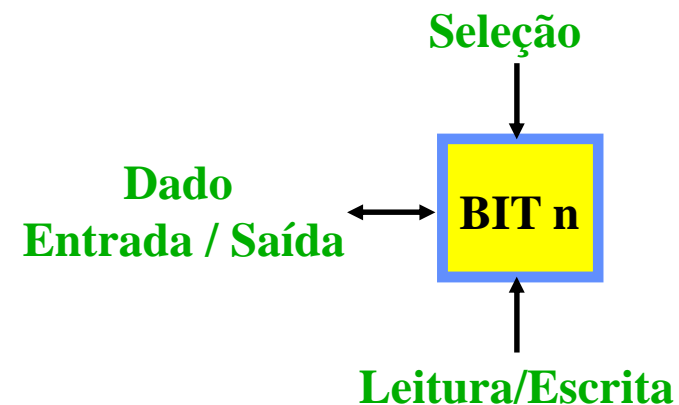


Célula de Memória RAM Estática

Célula de Memória (1 bit)



Memória de Leitura e Escrita

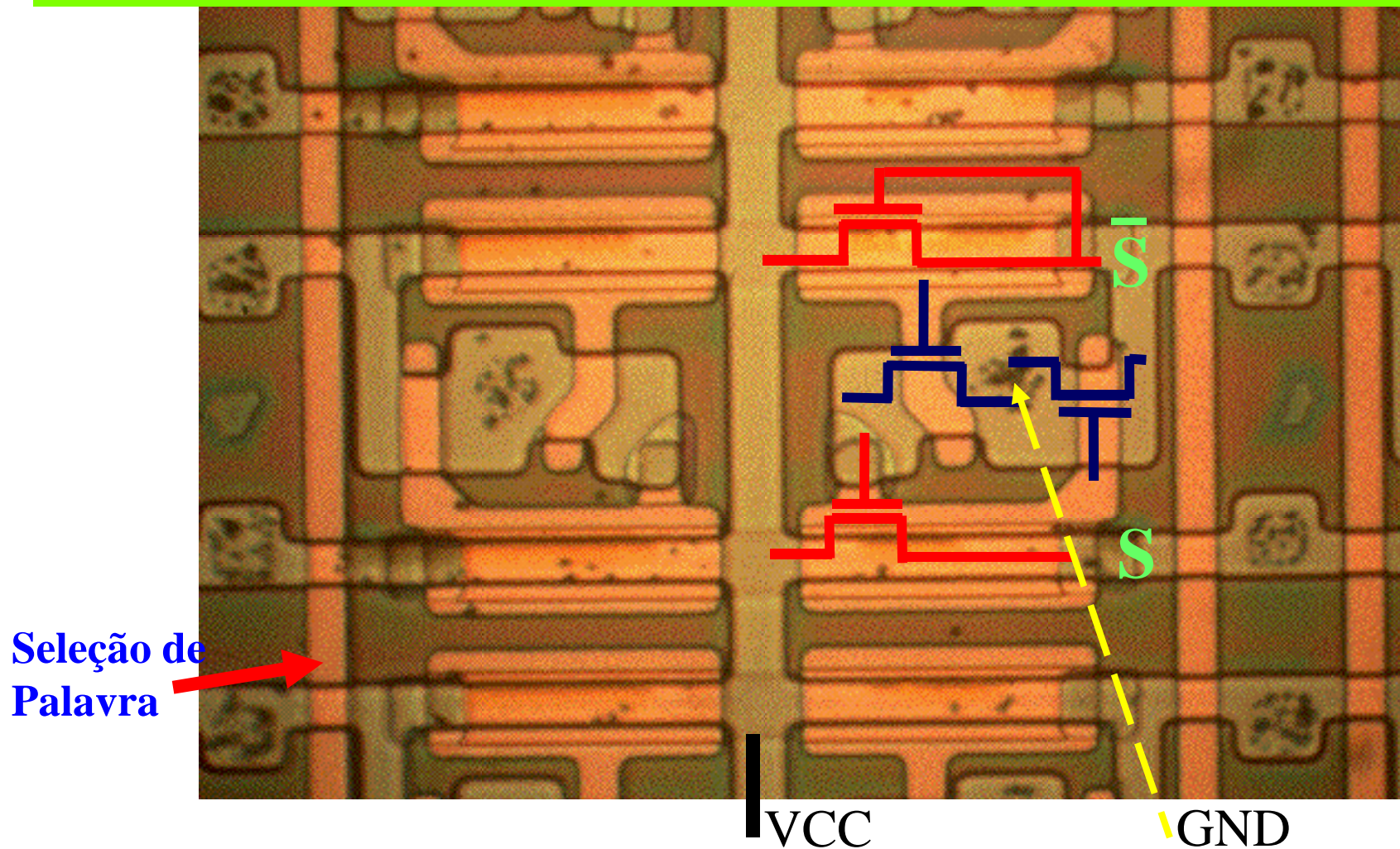


Barramento de dados: Dado e $\overline{\text{Dado}}$

Barramento de endereços: E_i (Seleção da Palavra)

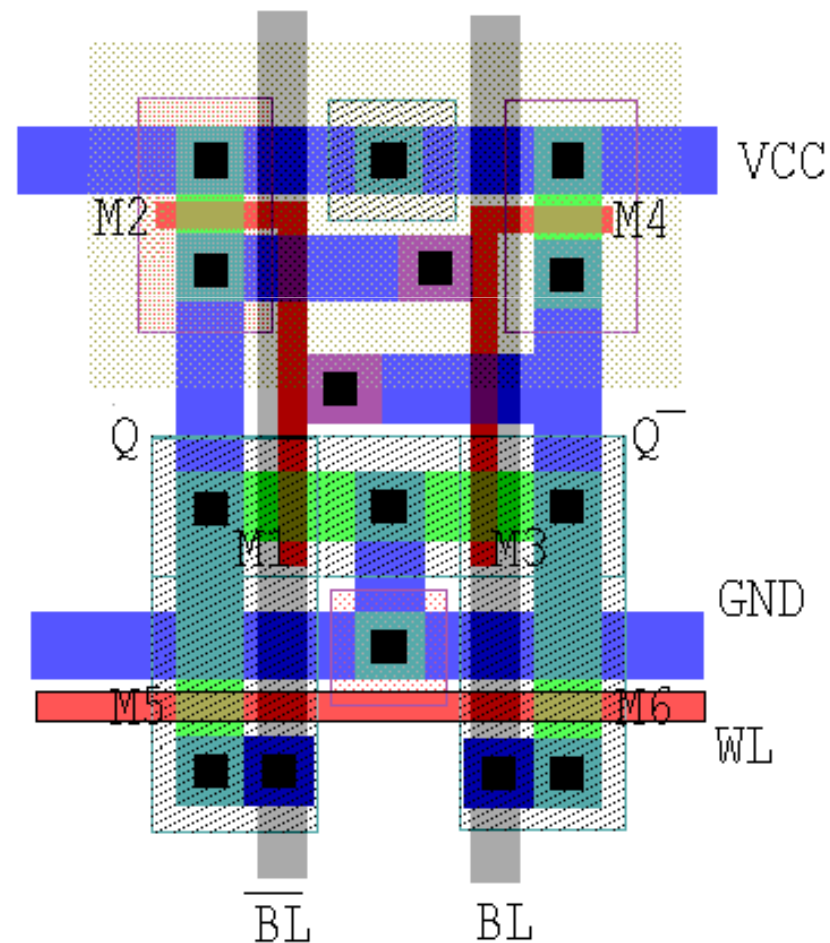
Memória RAM

Célula de Memória RAM do Banco de Registradores do processador 8085 (NMOS)

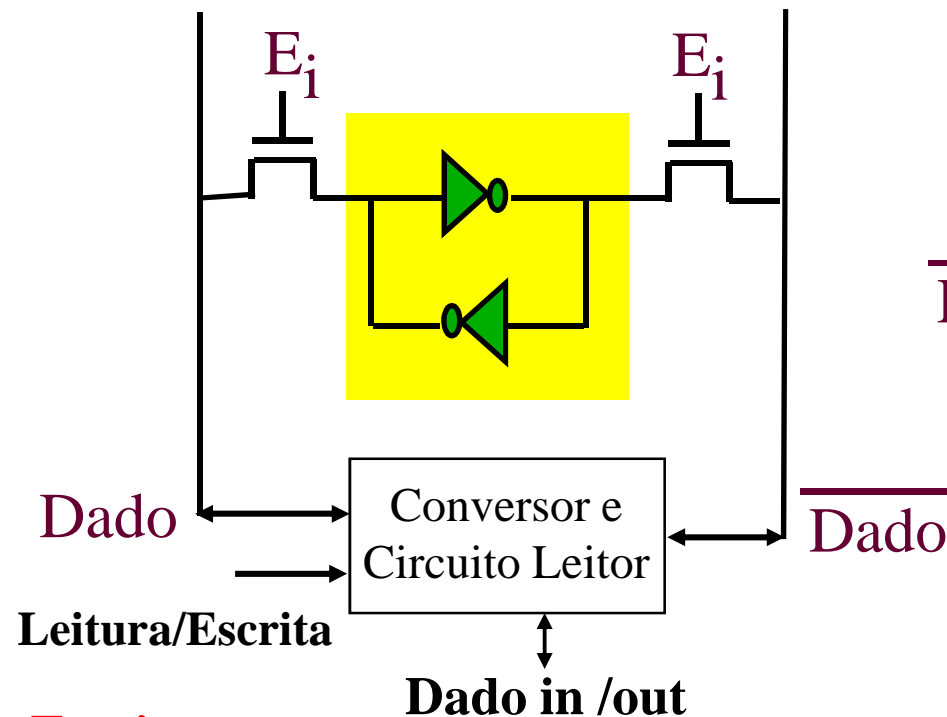


Memória RAM

Layout de uma célula SRAM 6T CMOS

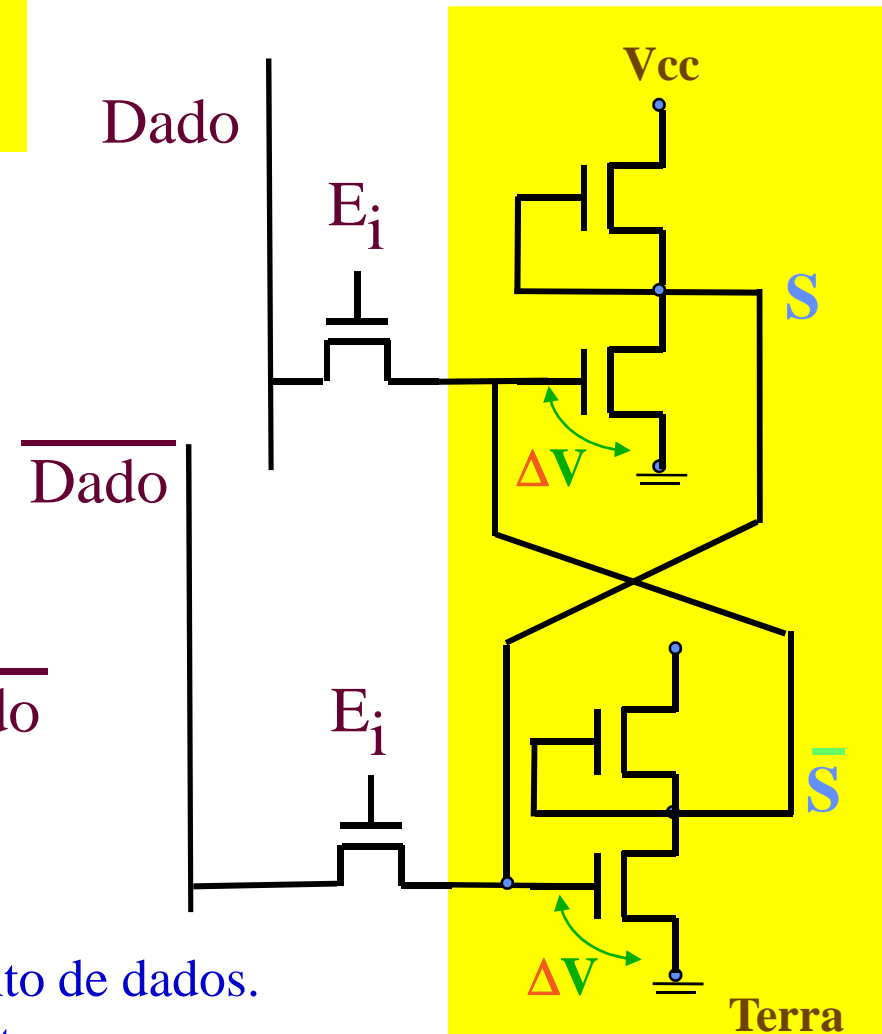


Memória RAM

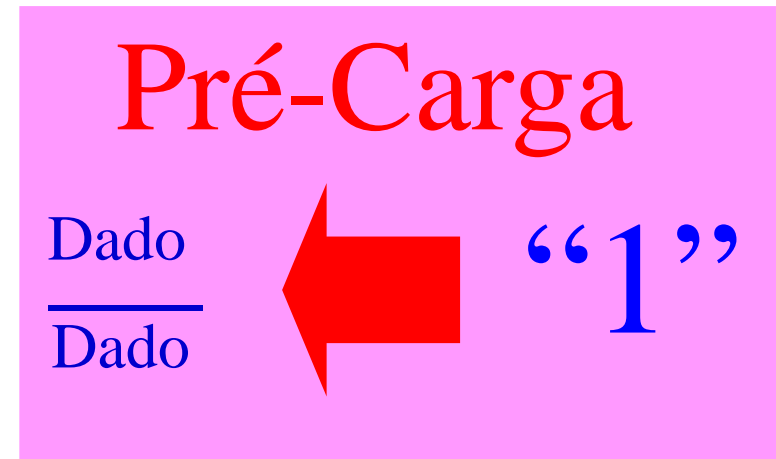
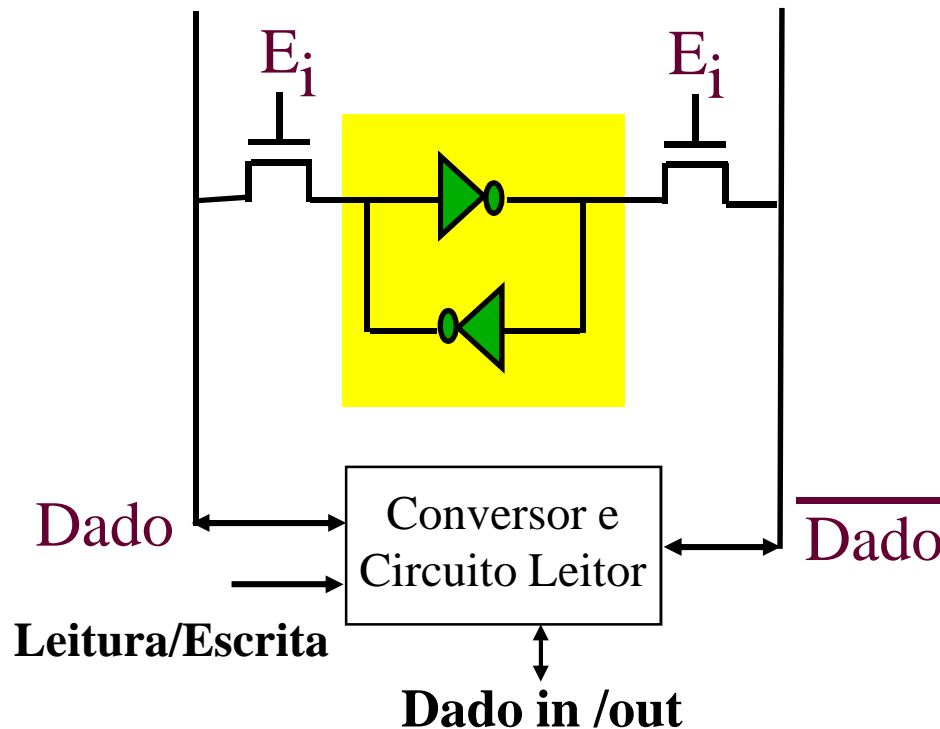


Escrita:

- 1- Coloca valor a ser escrito no barramento de dados.
- 2- Aciona endereço da palavra a ser escrita.
- 3- Valores existentes no barramento de dados são gravados na célula independentemente do valor existente anteriormente, devido a grande capacitância do barramento de dados.



Memória RAM



Leitura:

- 1- Carrega-se os barramento com o valor "1" (PRÉ-CARGA).
- 2- Aciona endereço da palavra a ser lida.
- 3- Valores existentes na célula memória são transferidos para o barramento, que se descarrega pelo "lado" que está em "zero".